

COXEM



**MEDIA SYSTEM
LAB**

WINDOW TO THE NANO WORLD

SCANNING ELECTRON MICROSCOPES
TABLE-TOP SEM : EM SERIES

EM-30N

New & Notable

EM-30N, which is a product of COXEM's steady investment for technology and development with a view to the era of nano-mechatronics, can deliver clear images without noise even at high magnification and scan an even wider area with its panorama feature.

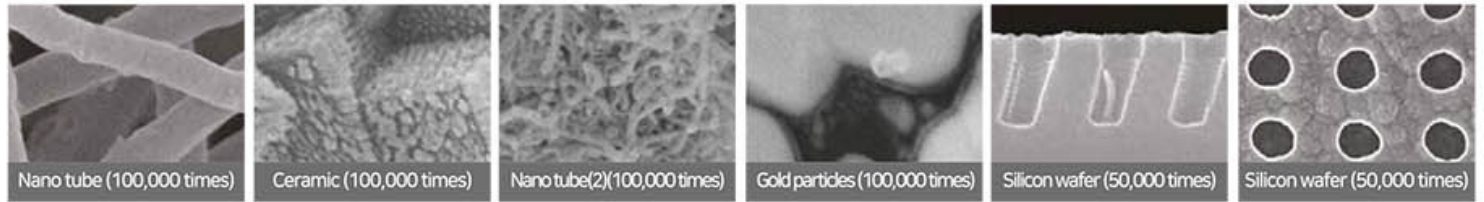
Also, its full compatibility with EDS delivers optimized performance.

Satisfactory both in performance and price, EM-30N will shine in all research areas and deliver superb results to the development and utilization of advanced technology.



Effect of High Resolution

EM-30N boasts the advantage that it enables high magnification observation of images. Moreover, it can effectively get high-resolution images by adjusting the voltage, operational distance, and electronic beam size.



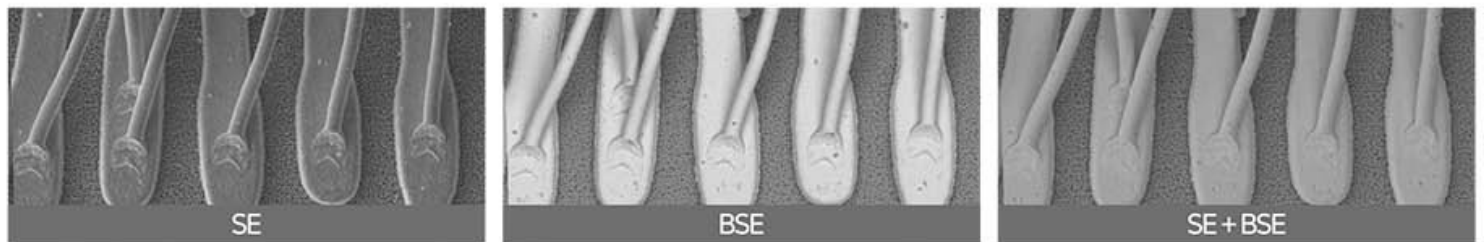
Dual Display / Signal Mixing Mode

Dual Display Mode

The dual display mode delivers SE and BSE images in a single-view presentation.

Signal Mixing Mode

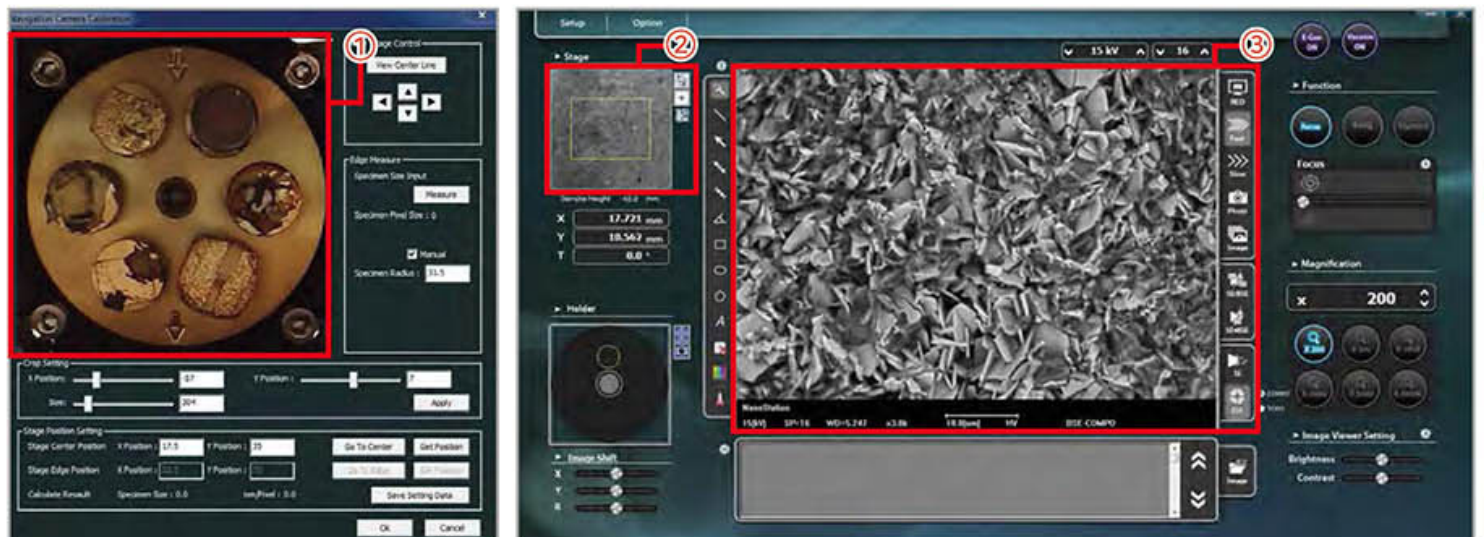
Combining SE and BSE images provides a single-view access to the forms and chemical composition of samples.



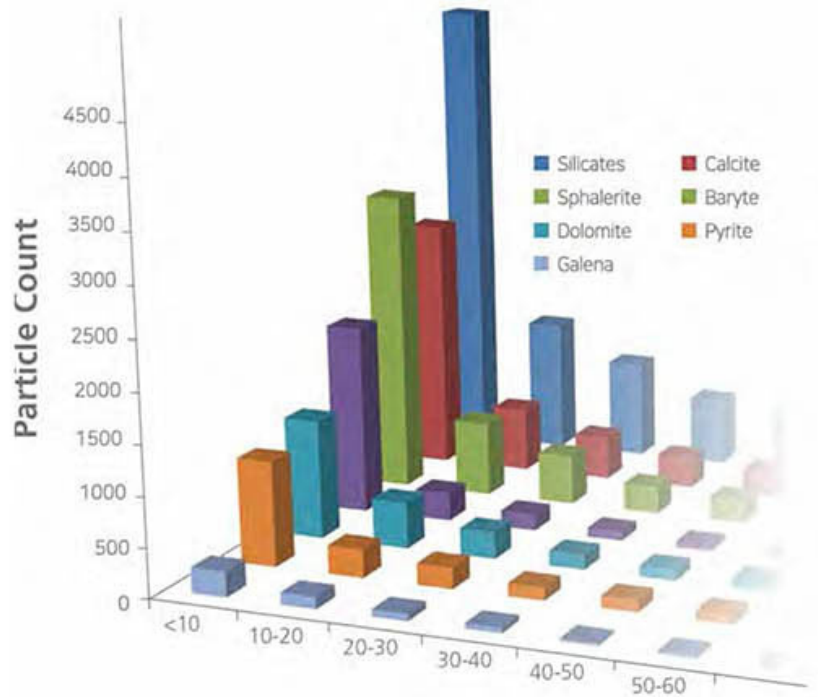
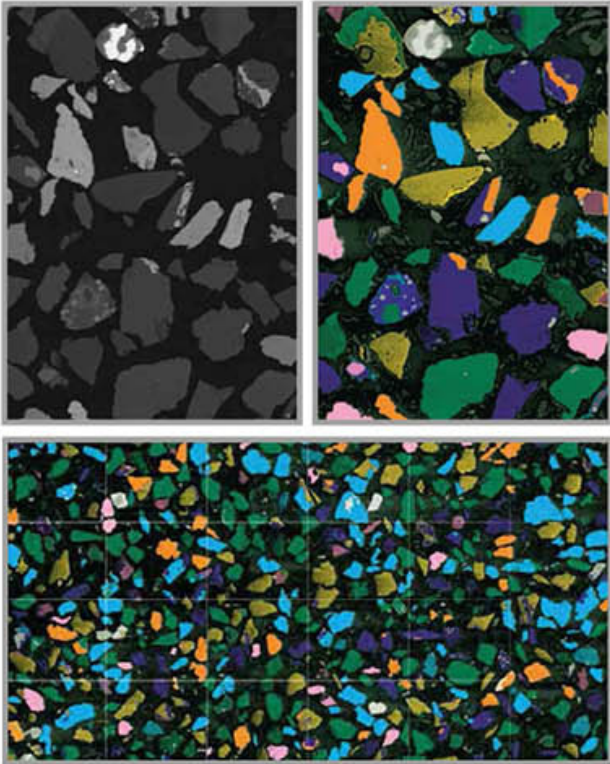
Duplex Navi

The NanoStation interface provides multiple means of navigation simply by clicking within any of the 3 different magnified views:

- ① A micro view using the CCD Navi Cam or Sample Holder map to move from sample to sample or areas of a large sample.
- ② A micro view using the low magnification MiniMap image with a Field of View (FOV) indicator to move within a sample
- ③ A nano view at the desired FOV allows movement by clicking in the image or using the Image Shift controls to make nanometer movements for perfect centering and alignment of sample features of interest

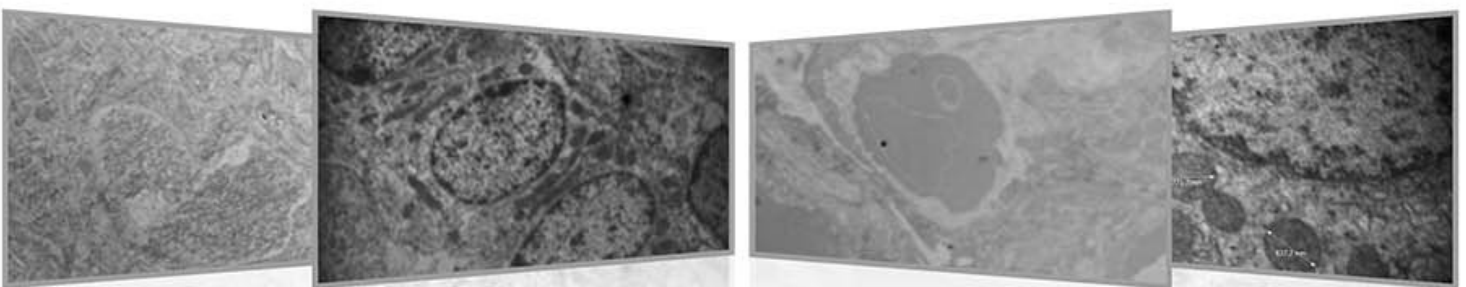


Particle Analysis



Particle analysis can be done with various methods, and accurate analysis is ensured even for composite samples.

STEM Analysis

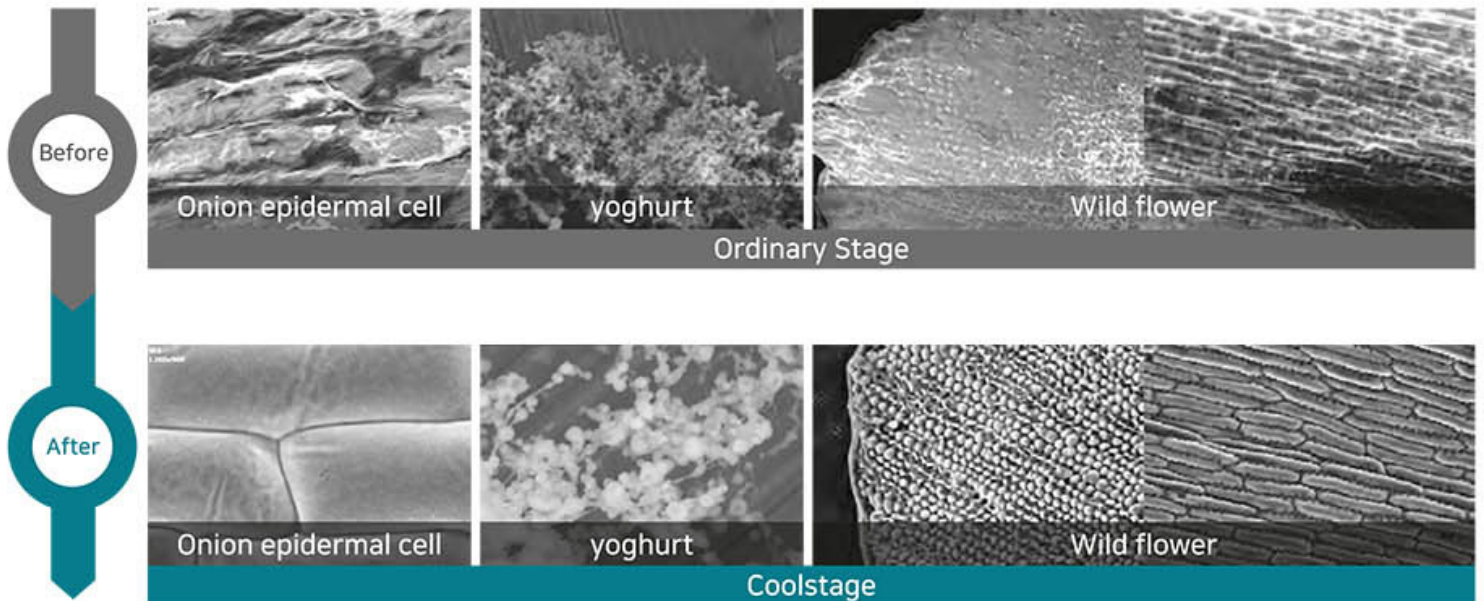


Coxem offers a true, retractable STEM detector enabling the EM-30N to perform TEM analysis of samples on standard TEM grids using our higher kV capability than other Tabletop SEM models. Imaging in both Bright and Dark field is possible as well as using EDS on up to 4 samples mounted simultaneously.

Coolstage



Performing SEM observations of moist samples requires a variety of pretreatments such as critical point drying and fixation. To shorten such complex sample preparation procedures, the COXEM Coolstage lowers the temperature of the sample to freeze internal moisture preventing the damaging effects of vacuum on delicate microstructure.



Control Temperature Range	-25°C~ 50°C
Temperature Precision	±0.1°C
Temperature Accuracy	±0.1°C
Sample Holder Size	18mm(d)

EM Series

Model	EM-30	EM-30N
Resolution	5nm	5nm
Magnification	Up to 150,000 X	Up to 150,000 X
Standard	SED	SED
		BSED(DP)
		Navi Cam
Optional		LV
		Diaphragm Pump
	BSED	STEM
	Coolstage	
	EDS(MPO)	
	EDS(MPO+Feature)	
	Panorama Ver 2.0	

Items	EM-30	EM-30N
SED	v	v
BSED	o	
BSED(DP)		v
NaviCam		v
LV		o
Panorama Ver 1.0		v
Panorama Ver 2.0		o
Diaphragm Pump		o
STEM		o
Coolstage	o	o
EDS(MPO)	o	o
EDS(MPO+Feature)	o	o

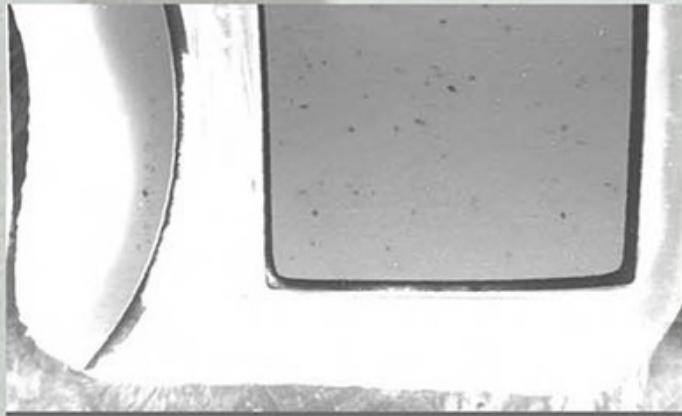
* v : standard

* o : optional

Low Vacuum Mode

Using the low vacuum (LV) mode, one can easily get an image of non-conductive samples or insulating materials without involving any special pretreatment.

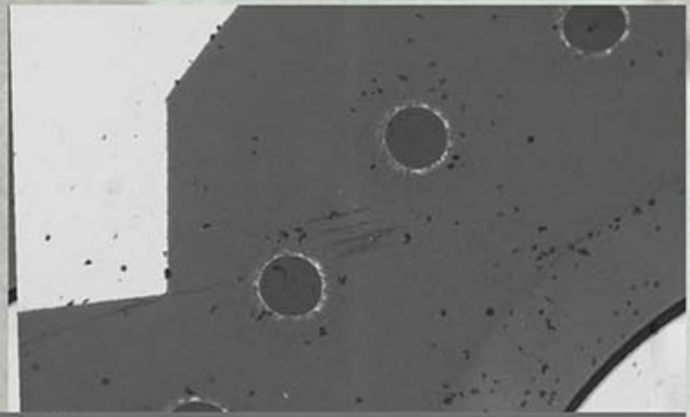
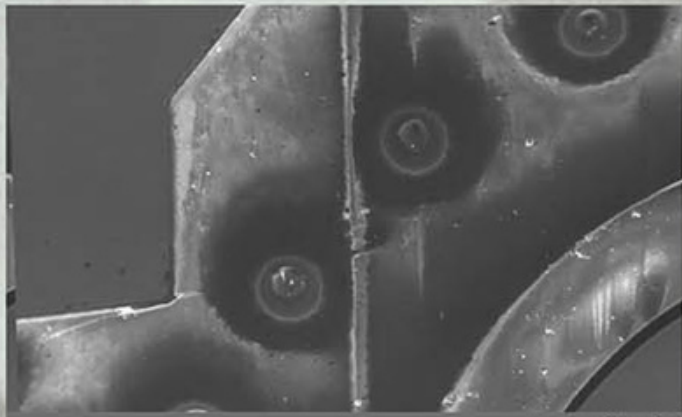
High Vacuum



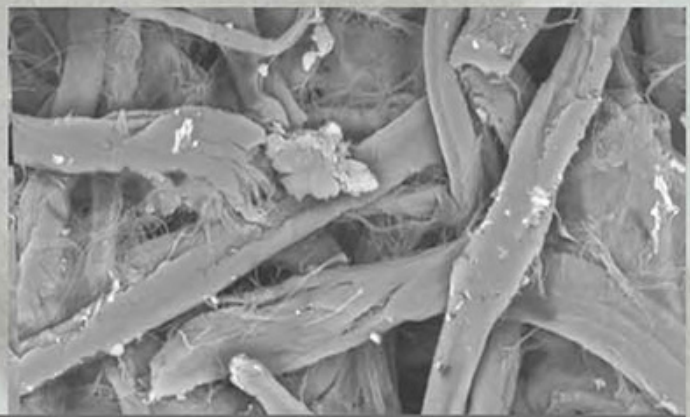
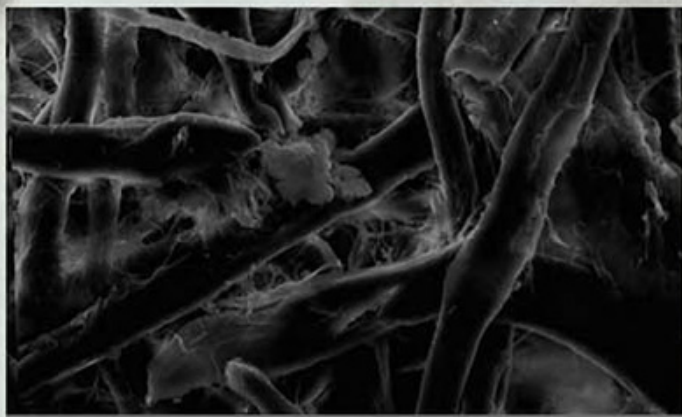
Low Vacuum



Semiconductor



Semiconductor



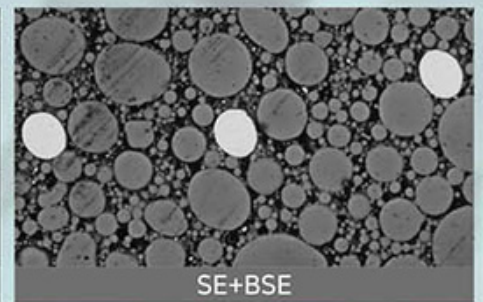
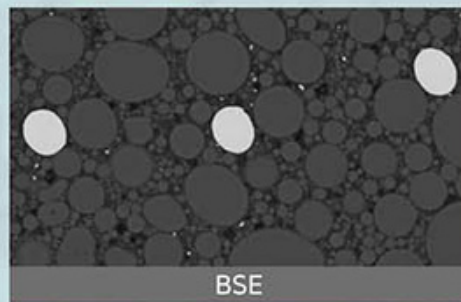
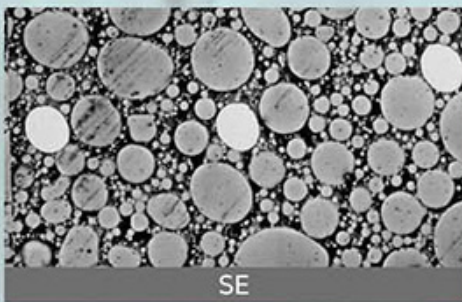
Paper

Dual Image / Signal Mixing Mode

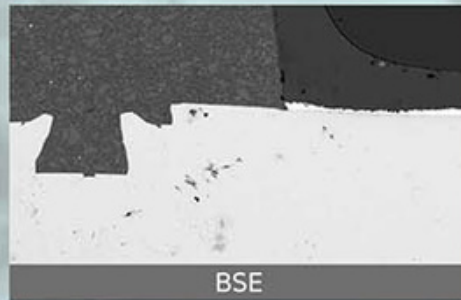
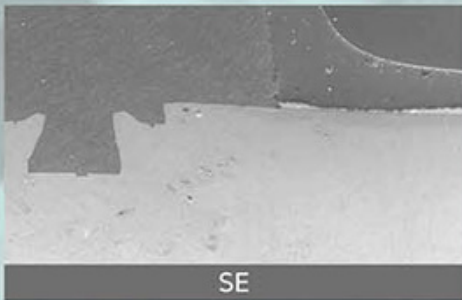
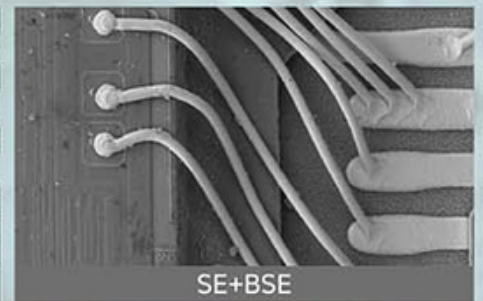
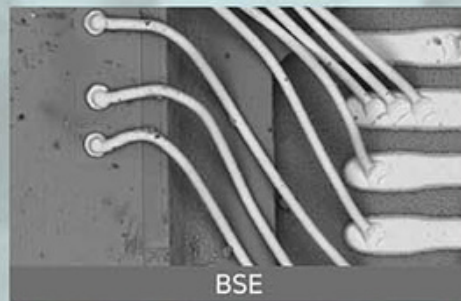
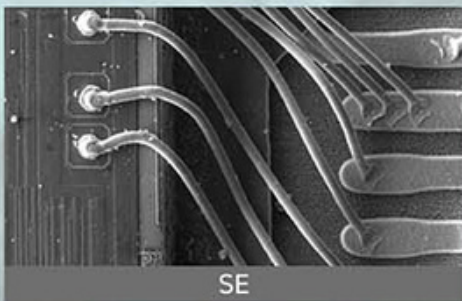
Electron microscope can realize images by collecting the different signals generated from samples with electronic beam.

The SE detector can get data as created by ruggedness by capturing secondary electrons (SE), and the backscattered electrons (BSE) collected with the BSE detector can get the elementary composition and stereoscopic images of the samples. It also performs signal merging, which presents the images of the forms and shapes of samples on a single screen.

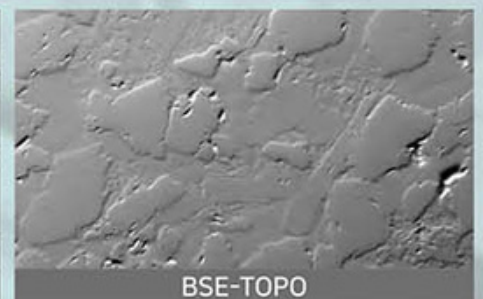
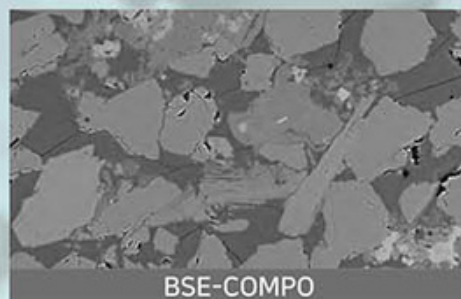
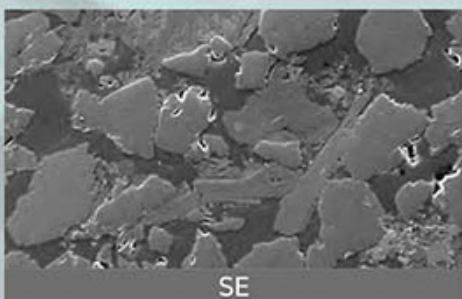
Metals



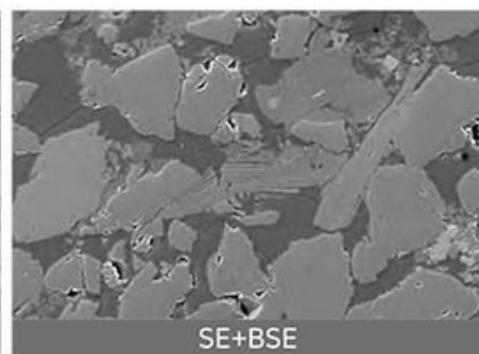
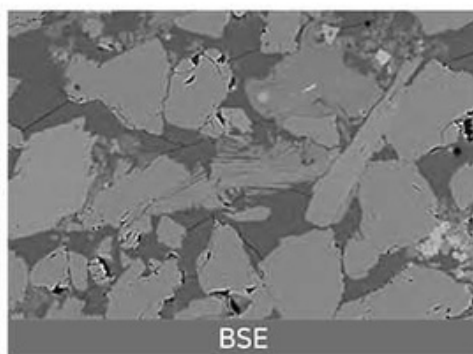
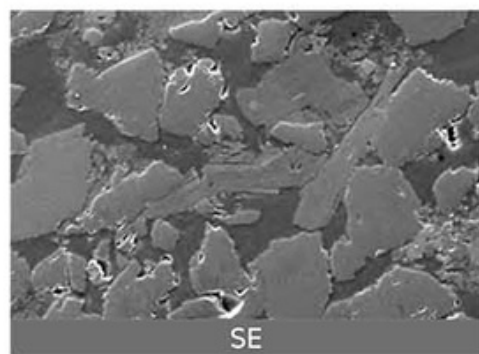
Semiconductor



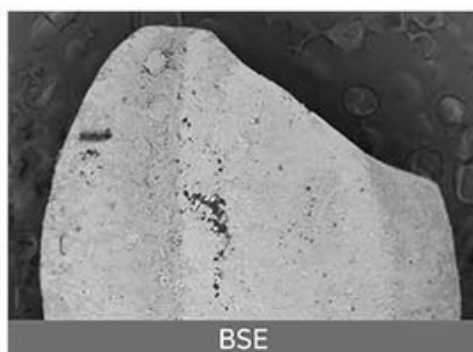
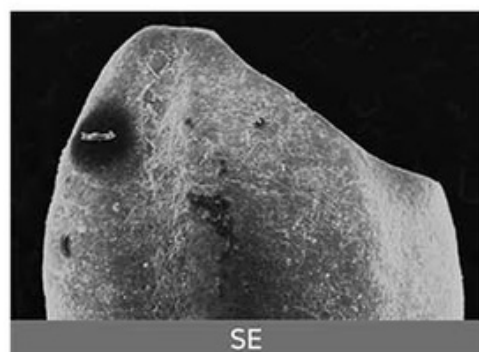
Minerals



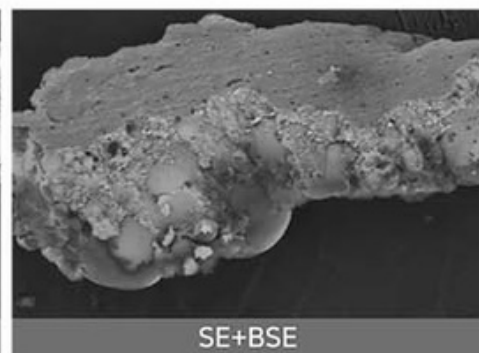
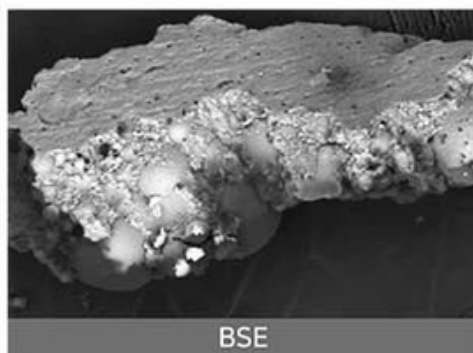
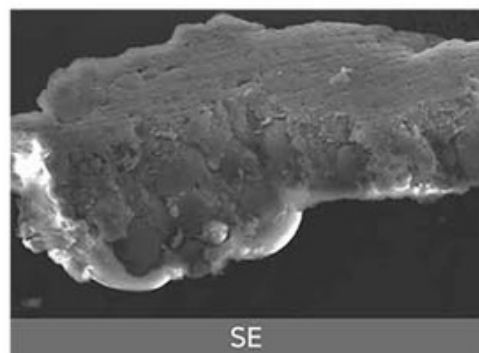
Minerals



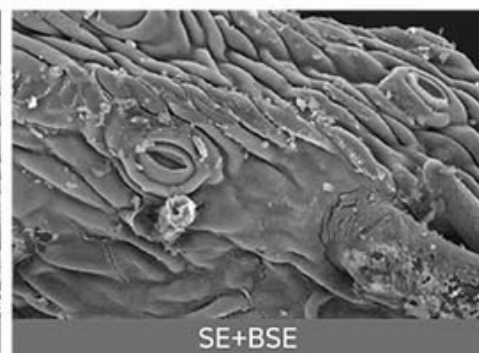
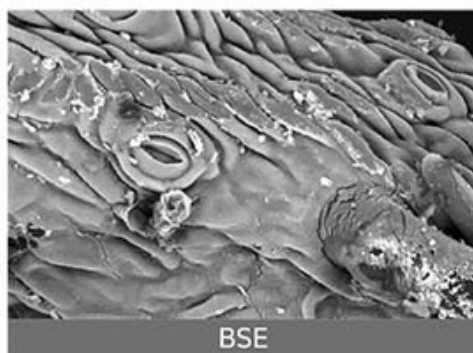
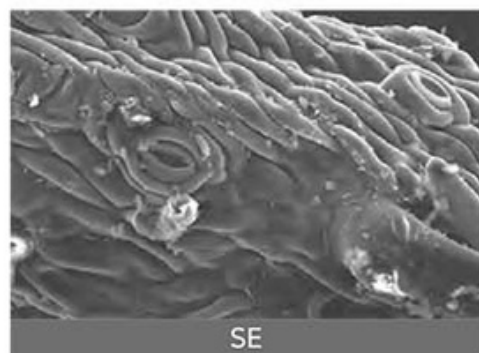
Rice



Rocks



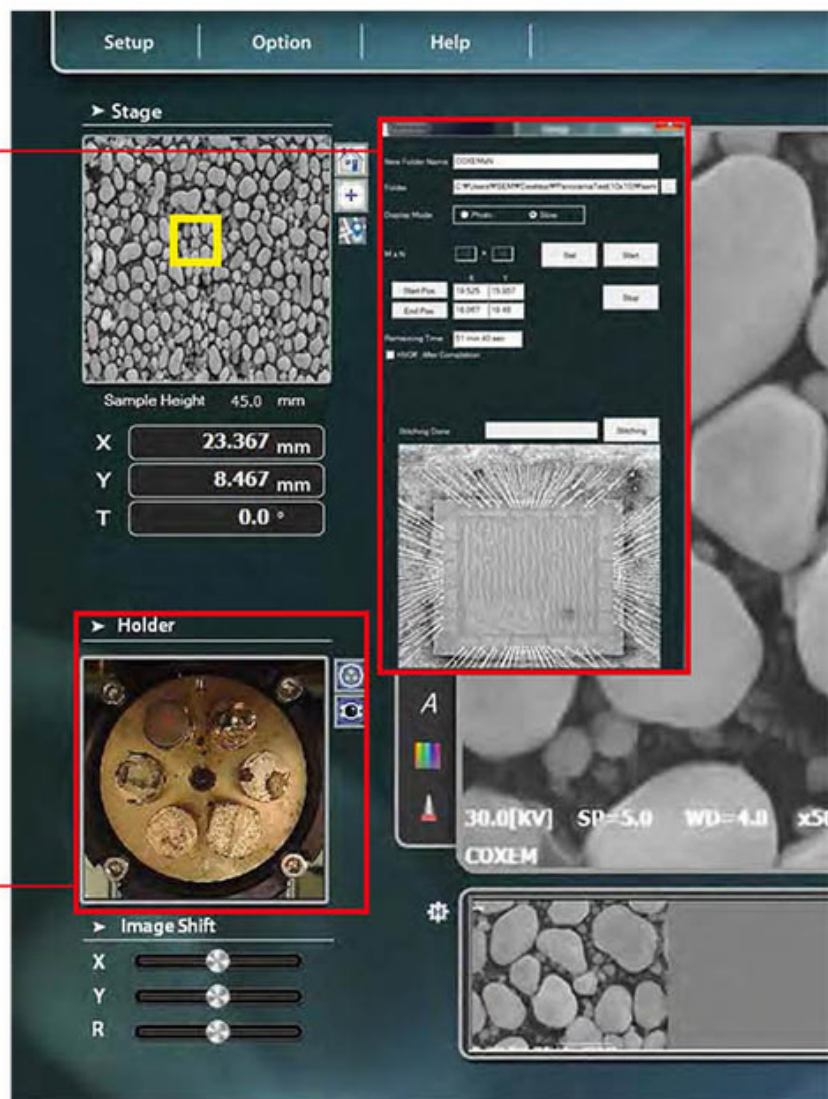
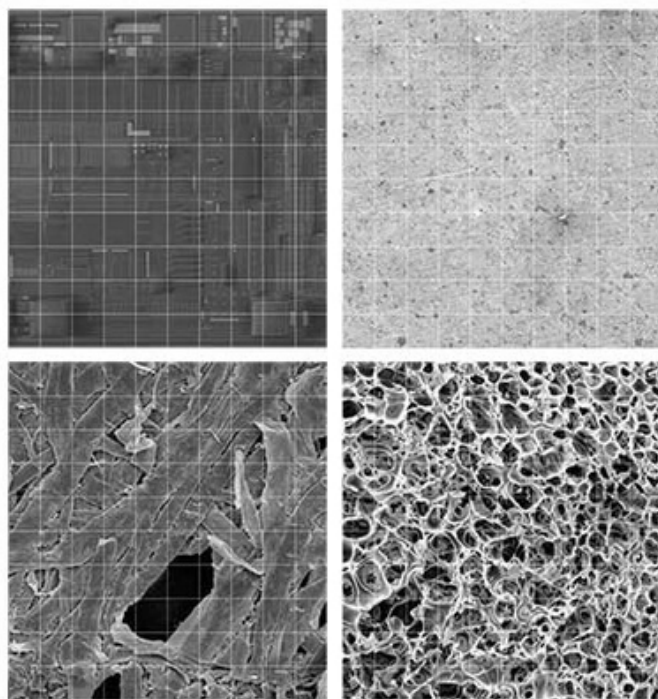
Tree bark



Nano Station

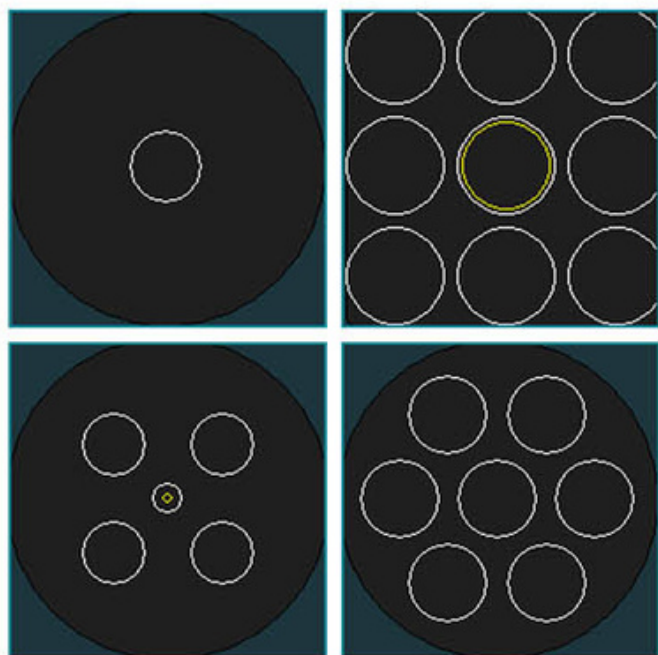
Panorama Shot

The panorama feature gets an image covering a very large scope at high magnification.



Multi-Sample holder

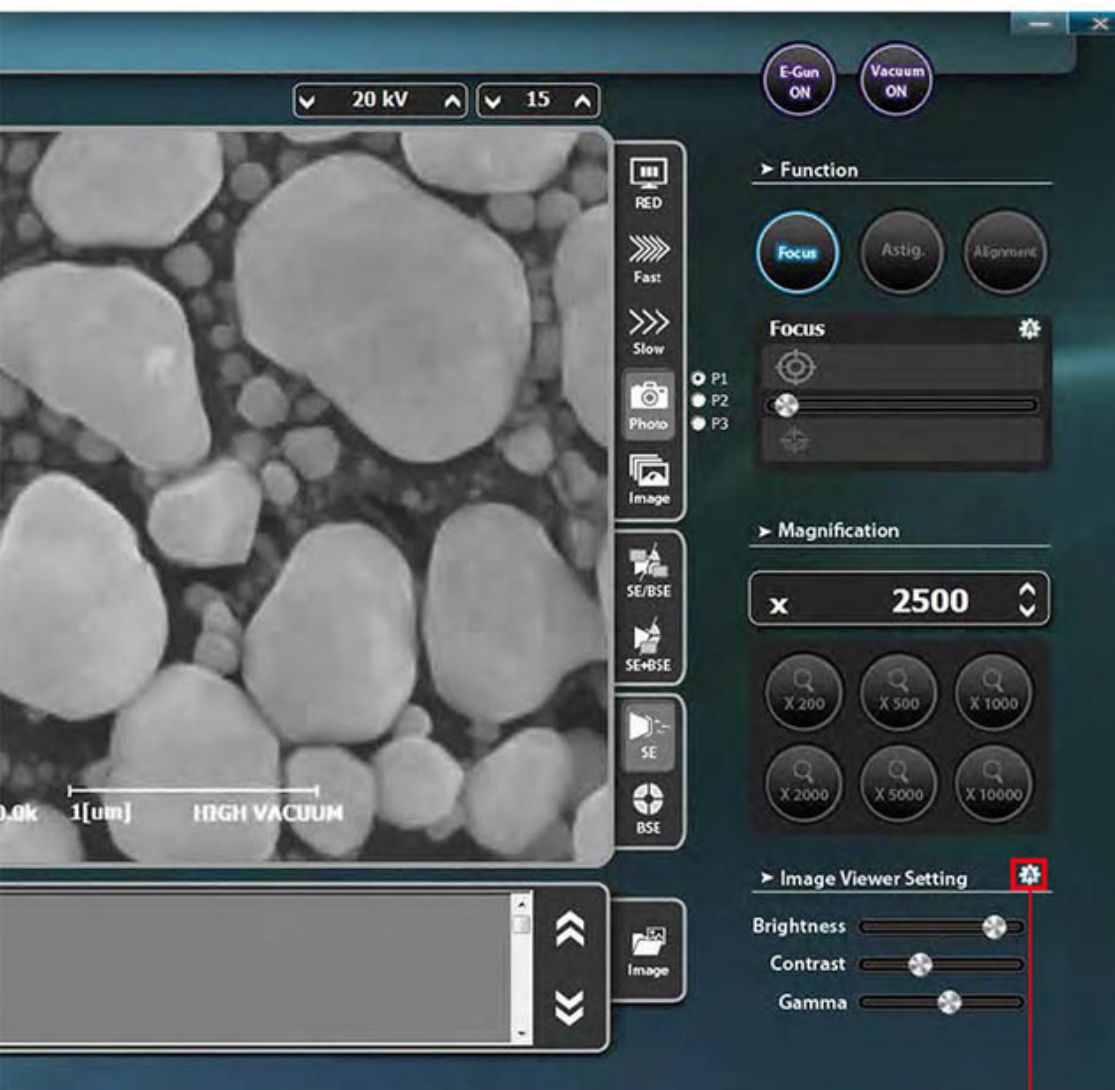
The SEM sample holder, which is available in various kinds, ensures easy, quick, and accurate measurement that adapts to sample location.



Navigation Camera

The built-in optical camera serves to locate actual samples and can move to desired locations.



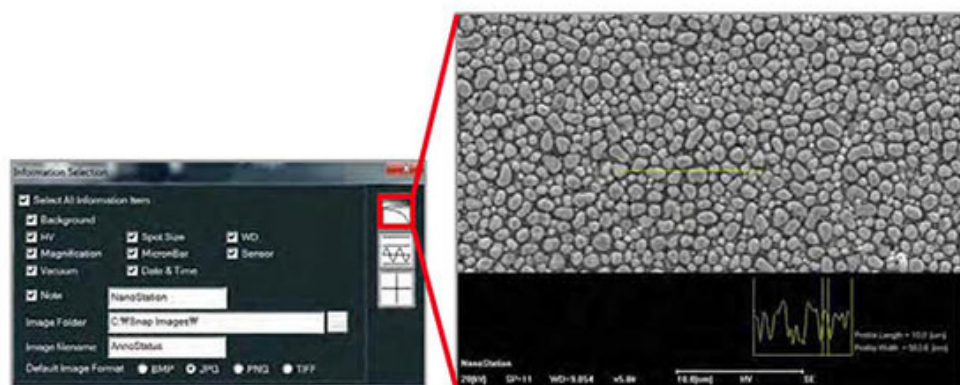


Auto Brightness / Contrast

The user can get an optimized image in 1 second.

Line Profile tool

The line-profiling technique provides more detailed data as the size and size can be measured more closely with nanoscale steps.

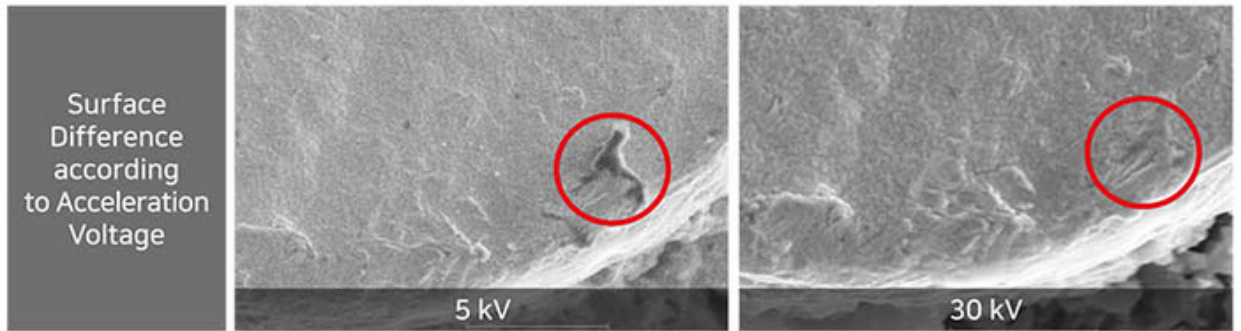


Buyer's Guide

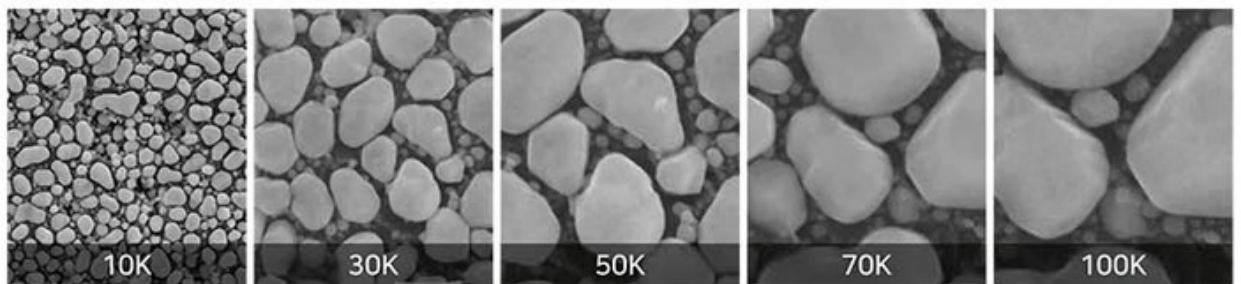
STEP 01

Which SEM is the best for you?

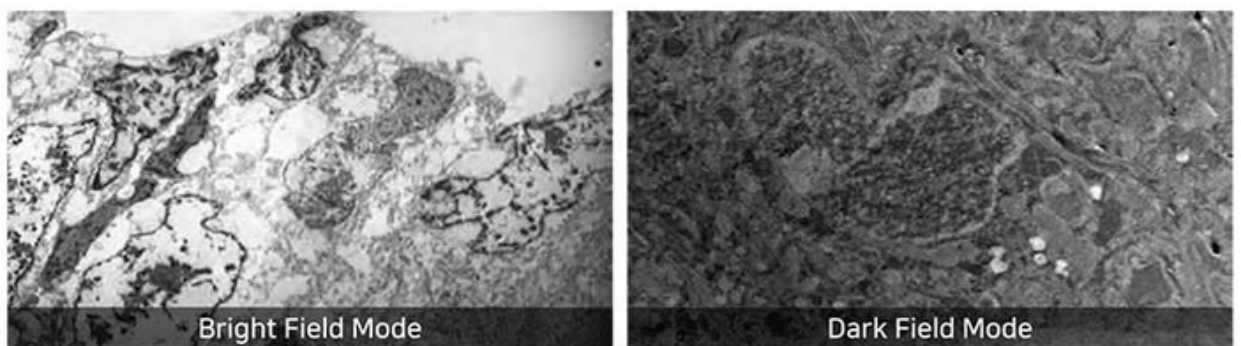
1. COXEM's SEM, which can freely adjust acceleration voltage between 1kV and 30kV, can analyze images in a way that fits the characteristics of a sample.



2. COXEM's SEM can perform analysis at varying magnification ranging from low to high. 15x to 150,000x



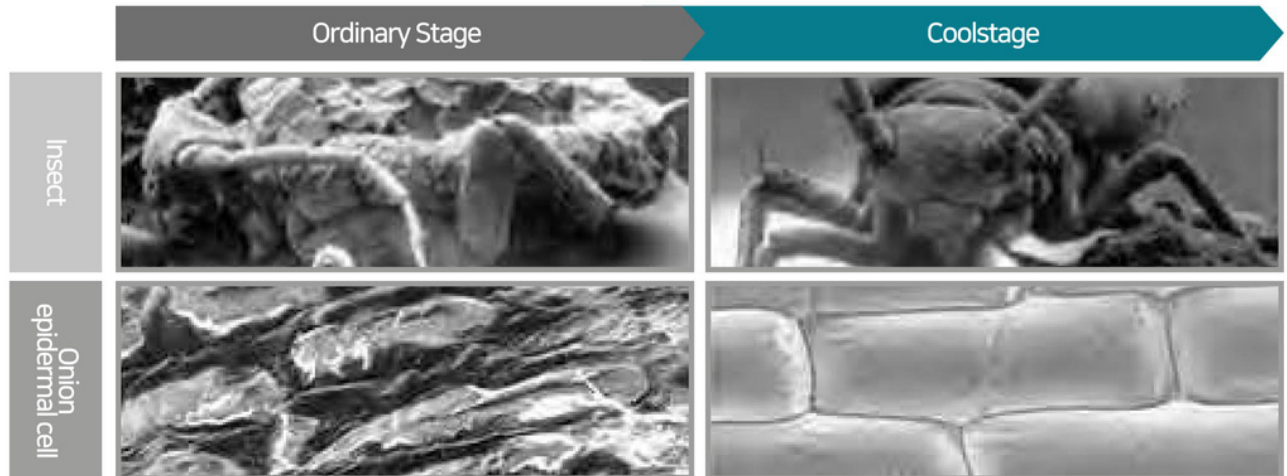
3. COXEM's SEM, which inserts the STEM detector, can perform the TEM analysis with its sensor, thus able to analyze asbestos, cell tissue, and nano-structures among others.



4. COXEM's SEM can include EDS in addition and analyze various particles including features, GSR, and steel.



5. COXEM's SEM, which uses Coolstage, can analyze live specimens (such as fungi, cells, and insects) by freezing them and get images of microstructures free from damage.



6. COXEM's SEM is convenient and easy to install.
Simply connect power, USB and the provided vacuum pump.



Installable by the user *



* Our local Distributors provide Installation and Training Service when necessary

How best can I buy the product?

1. If you have any sample to analyze, send it to COXEM.
As our Demonstration Room has pretreatment equipment including sputter, polisher, and cool stage, we can analyze various kinds of specimens.
2. Based on the analysis data, we compare, analyze and evaluate the resulting values as measured against the customer's expectations.
3. Check the analysis parameters desired about the sample and seek consultation.
Options may be added according to purposes (such as SE, BSE, and EDS).
4. Select, buy, and get training for the equipment suitable for the sample analysis.
Training is provided on how to effectively use the equipment with a view to its installation.
5. In case a customer needs additional training, please consult your local distributor.

STEP
02



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